

Irish Standard I.S. EN IEC 61788-26:2020

Superconductivity - Part 26: Critical current measurement - DC critical current of RE-Ba-Cu-O composite superconductors

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I.S. EN IEC 61788-26:2020 is the adopted Irish version of the European Document EN IEC 61788-26:2020, Superconductivity - Part 26: Critical current measurement - DC critical current of RE-Ba-Cu-O composite superconductors

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# EN IEC 61788-26

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# **EUROPÄISCHE NORM**

August 2020

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**English Version** 

# Superconductivity - Part 26: Critical current measurement - DC critical current of RE-Ba-Cu-O composite superconductors (IEC 61788-26:2020)

Supraconductivité - Partie 26: Mesurage du courant critique - Courant critique continu des composites supraconducteurs de RE-Ba-Cu-O (IEC 61788-26:2020) Supraleitfähigkeit - Teil 26: Messung des kritischen Stroms - Kritischer DC-Strom von RE-Ba-Cu-O Komposit Supraleitern (IEC 61788-26:2020)

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### EN IEC 61788-26:2020 (E)

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# IEC 61788-26

Edition 1.0 2020-06

# INTERNATIONAL STANDARD

NORME INTERNATIONALE

Superconductivity – Part 26: Critical current measurement – DC critical current of RE-Ba-Cu-O composite superconductors

Supraconductivité – Partie 26: Mesurage du courant critique – Courant critique continu des composites supraconducteurs de RE-Ba-Cu-O





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Supraconductivité – Partie 26: Mesurage du courant critique – Courant critique continu des composites supraconducteurs de RE-Ba-Cu-O

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# INTERNATIONAL ELECTROTECHNICAL COMMISSION

# SUPERCONDUCTIVITY -

# Part 26: Critical current measurement – DC critical current of RE-Ba-Cu-O composite superconductors

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90/455/FDIS	90/458/RVD

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# INTRODUCTION

In 1986, superconductivity in some perovskite type materials containing copper oxides at temperatures far above the critical temperatures of metallic superconductors was discovered. In 1987, it was discovered that Y-Ba-Cu-O (YBCO) has a critical temperature ( $T_c$ ) of 93 K. After a quarter century, the RE-Ba-Cu-O (REBCO, RE = rare earth) superconductors became commercially available.

In 2013, VAMAS-TWA 16 started working on the critical current measurement methods in REBCO superconductors. In 2014, an international round robin test (RRT) on the critical current measurement method for REBCO superconductors was conducted that was led by VAMAS-TWA 16. 10 institutions/universities/industries from five countries participated. The prestandardization work of VAMAS was taken as a base for this document, on the DC critical current test method of REBCO composite superconductors.

The test method covered in this document is intended to give an appropriate and accepted technical base to engineers working in the field of superconductivity technology.

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# SUPERCONDUCTIVITY -

# Part 26: Critical current measurement – DC critical current of RE-Ba-Cu-O composite superconductors

# 1 Scope

This part of IEC 61788 specifies a test method for determining the DC critical current of short RE (rare earth)-Ba-Cu-O (REBCO) composite superconductor specimens that have a shape of straight flat tape. This document applies to test specimens shorter than 300 mm and having a rectangular cross section with an area of  $0,03 \text{ mm}^2$  to  $7,2 \text{ mm}^2$ , which corresponds to tapes with width ranging from 1,0 mm to 12,0 mm and thickness from 0,03 mm to 0,6 mm.

This method is intended for use with superconductor specimens that have critical current less than 300 A and *n*-values larger than 5 under standard test conditions: the test specimen is immersed in liquid nitrogen bath at ambient pressure without external magnetic field during the testing. Deviations from this test method that are allowed for routine tests and other specific restrictions are given in this document.

# 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-815, International Electrotechnical Vocabulary (IEV) – Part 815: Superconductivity

# 3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60050-815 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following URLs:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp/

#### 3.1

### constant sweep rate method

U-I data acquisition method where a current is swept at a constant rate from zero to a current above  $I_{c}$ , and where the U-I data are acquired continuously or frequently

### 3.2

### ramp-and-hold method

U-I data acquisition method where a current is swept in stages from zero to a current above  $I_c$ , where the current is held for an appropriate amount of time at each stage, and where the U-I data are acquired continuously or frequently



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